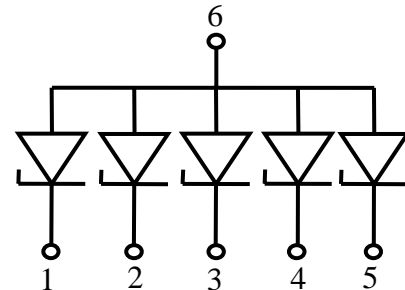
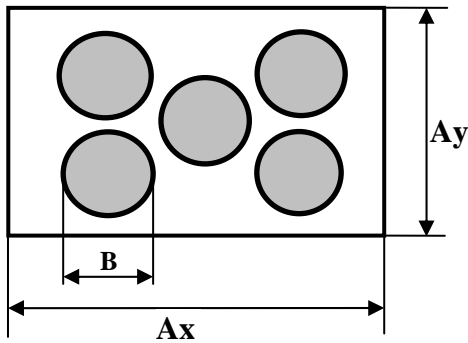


## KS-5.0V5L1, KS-5.0V5L2

Chip low capacitance 5- fold ESD protection diode.



**Mechanical date:**  $A_x=480\mu\text{m}$ ,  $A_y=370\mu\text{m}$ ,  $B=90\mu\text{m}$

**Chip thickness:** a)  $230\pm 20\mu\text{m}$  – for KS-5,0V5L1;  
b)  $138\pm 12\mu\text{m}$  – for KS-5,0V5L2.

**Scribe Line width** -  $60\mu\text{m}$ .

**Top Metal:** Al - for wire bonding,  $d=2.2\pm 0.2\mu\text{m}$ .

**Back side - Anode:** Ti-Ni-Ag for soldering.

**Schematic and pinning diagram.**

### Limiting values

| Parameter                 | Symbol    | Conditions              | Value                       | Unit |
|---------------------------|-----------|-------------------------|-----------------------------|------|
| Reverse Stand-off voltage | $V_{RWM}$ | -                       | 5                           | V    |
| Peak Pulse Power          | $P_{pp}$  | $t_p=8/20\mu\text{s}$   | 25*                         | W    |
| Peak Pulse Current        | $I_{pp}$  | $t_p=8/20\mu\text{s}$   | 2.5*                        | A    |
| Electrostatic Discharge   | $V_{ESD}$ | IEC 61000-4-2, level 4. | >8 (Contact);<br>>15 (Air). | kV   |
| Max.junction temperature  | $T_j$     | -                       | +150                        | °C   |

### Characteristics ( $T_j=25^\circ\text{C}$ )

| SYMBOL   | PARAMETER               | CONDITIONS   | MIN. | TYP. | MAX.       | UNIT |
|----------|-------------------------|--|------|------|------------|------|
| $V_{BR}$ | Breakdown voltage       | $I_R=1\text{mA}$   | 6.45 | -    | 7.15       | V    |
| $I_R$    | Reverse leakage current | $V=5\text{V}$  | -    | 5    | 25         | nA   |
| $V_{CL}$ | Clamping Voltage        | $I_{pp}=1.0\text{A}$ , $t_p=8/20\mu\text{s}$<br>$I_{pp}=2.5\text{A}$ , $t_p=8/20\mu\text{s}$ | -    | -    | 10*<br>12* | V    |
| $C_j$    | Diode capacitance       | $V_R=0\text{V}$ , $f=1\text{MHz}$  | -    | 16   | 19         | pF   |

\*- For Device testing